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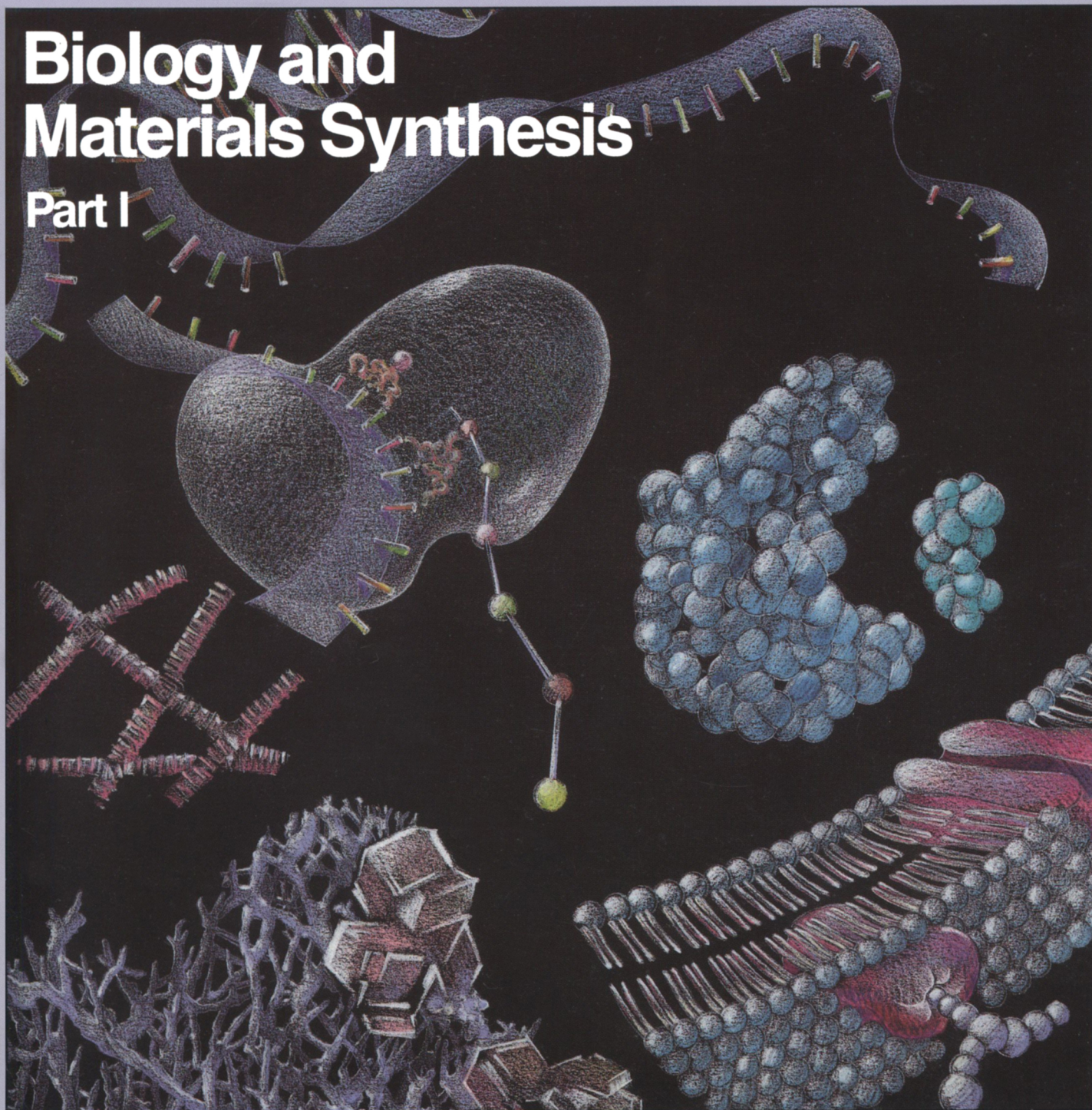
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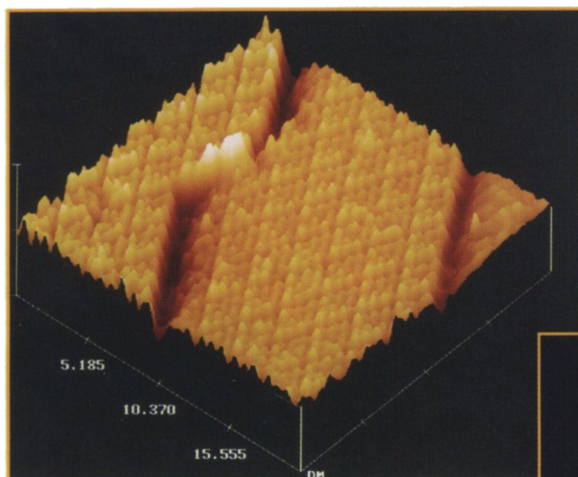


Biology and Materials Synthesis

Part I

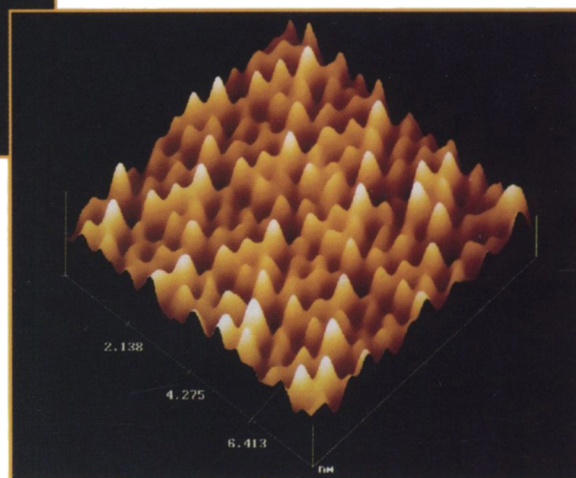


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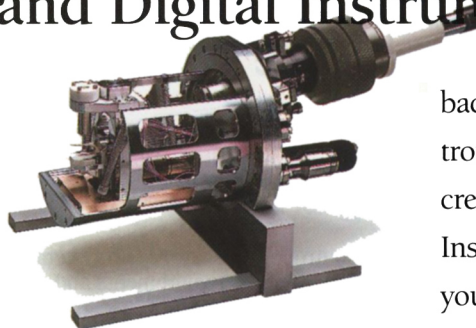
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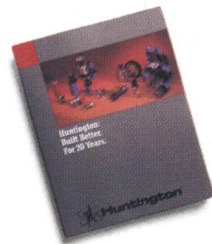
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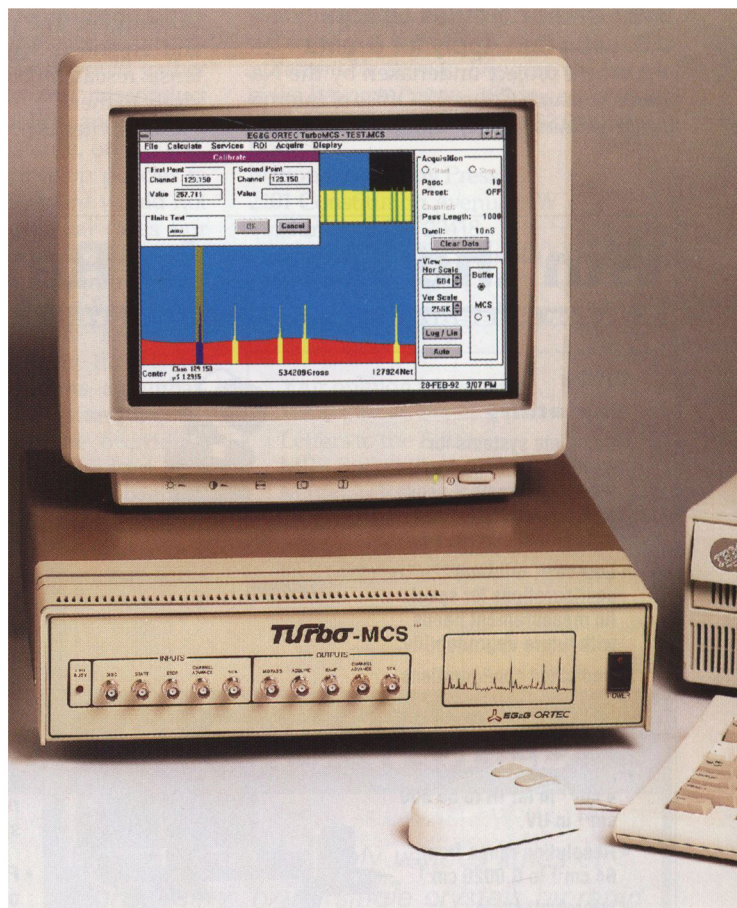
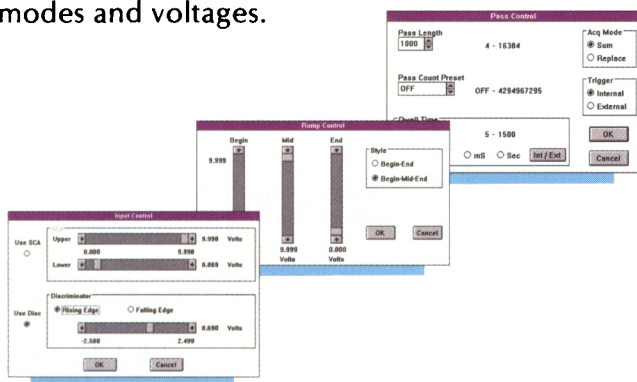


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BIOLOGY AND MATERIALS SYNTHESIS

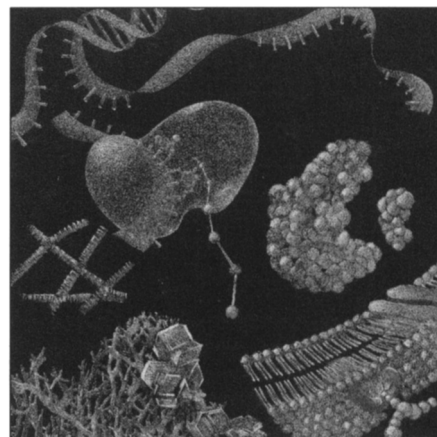
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ON THE COVER: Artist Marilee Bailey's view of Biomaterials. The double-stranded helix of DNA opens to allow transcription and synthesis of mRNA, which is translated on the ribosome to produce the genetically defined amino acid sequence of the protein. Some proteins fold to become enzymes, catalyzing reactions leading to the synthesis of materials. Others fold and become embedded in self-assembling membranes and, in some cases—with attached carbohydrate groups—function in transport electron transfer, sensing, adhesion. Still other proteins serve as matrices for biomineralization, while others assemble into fibers such as silk or collagen for roles as structural materials. Detailed information on biology and materials synthesis begins on page 24.

About the Materials Research Society

The Materials Research Society (MRS), a nonprofit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 10,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and more than 40 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is an affiliate of the American Institute of Physics.

MRS publishes symposium proceedings, *MRS Bulletin*, *Journal of Materials Research*, and other publications related to current research activities.

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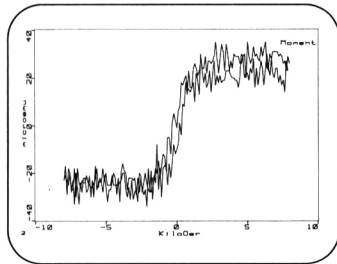
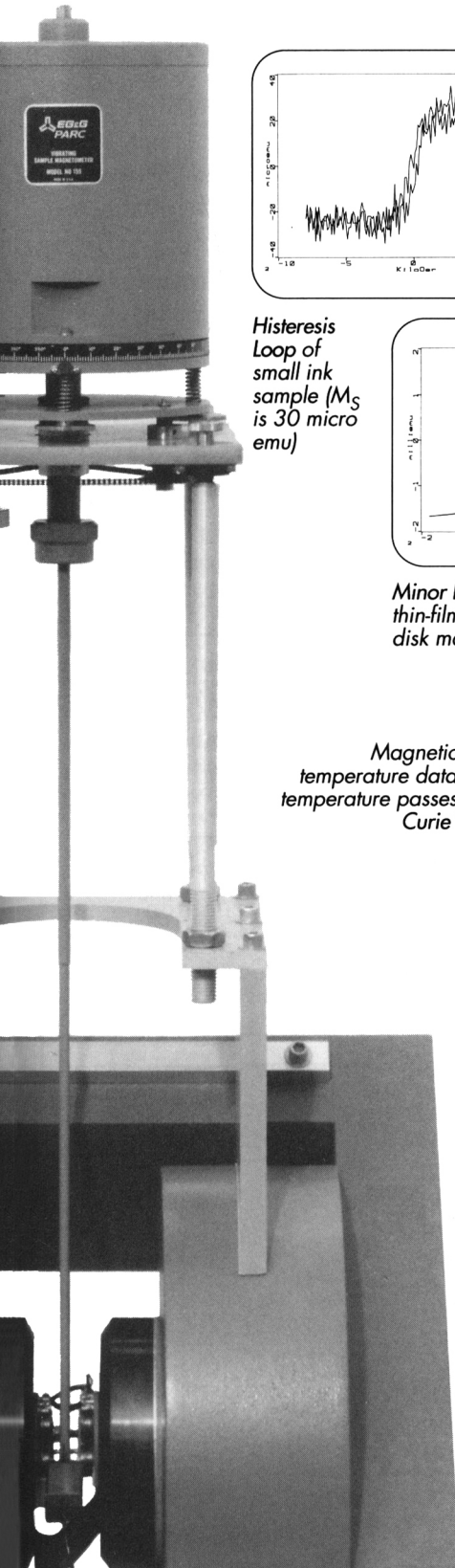
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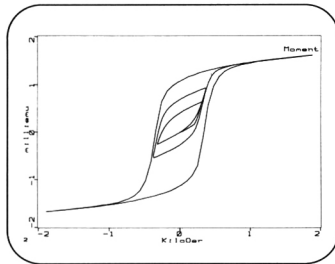
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Nothing Beats Good Data



Hysteresis Loop of small ink sample (M_S is 30 micro emu)



Minor Loops of thin-film, hard-disk material

Magnetic moment vs. temperature data of nickel as temperature passes through the Curie Temperature

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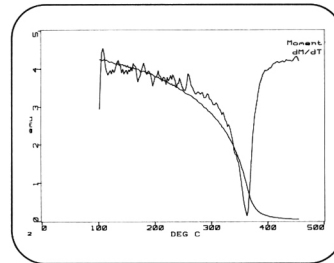
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Breakdown Electric Field - E_B [V/cm (for 1000 V operation)]	2.5×10^6	3×10^5	2.5×10^5	<ul style="list-style-type: none"> • High Power • High Density Integration
Thermal Conductivity (W/cm \cdot K @RT)	4.9	0.5	1.5	<ul style="list-style-type: none"> • High Thermal Conductivity (greater than any metal)
Saturated Electron Drift Velocity [cm/sec (@ $E \geq 2 \times 10^5$ V/cm)]	2.0×10^7	1.0×10^7	1.0×10^7	<ul style="list-style-type: none"> • High Frequency Operation in High Electric Fields



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